

# INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Sheet **B1** of **B1**

## Complete if Known

Application Number	10/719,192
Filing Date	November 21, 2003
First Named Inventor	Seung-Kwon Baek et al.
Art Unit	2611
Examiner Name	Leila Malek
Attorney Docket Number	5649-1185

## U.S. PATENT DOCUMENTS AND APPLICATIONS

Examiner Initials*	Cite No.	Document Number Number-Kind Code (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		US-			
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## FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No.	Foreign Patent Document Country Code, Number, Kind Code (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T
/LM/	1.	JP 2001-136149 A	05-18-2001	Nippon Telegr. & Teleph. Corp.		Abstract
/LM/	2.	JP 2001-022731 A	01-26-2001	Yamatate Corp.		Abstract
/LM/	3.	WO 02/48901 A2	06-20-2002	IHP GMBH-Innovations For High Performance Microelectronics/Institut Für Innovative Mikroelektronik (DE)		Abstract

## NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T
/LM/	4.	Japanese Office Action (2 pages) corresponding to Japanese Patent Application No. 2003-394450; Mailing Date: April 8, 2009.	No

iDoc# 773046

Examiner Signature	/Leila Malek/	Date Considered	- 07/22/2009
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